

FGA70N33BTD **330V, 70A PDP IGBT**

Features

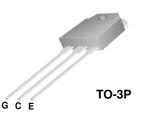
- · High current capability
- Low saturation voltage: V_{CE(sat)} =1.7V @ I_C = 70A
- High input impedance
- · Fast switching
- · RoHS Compliant

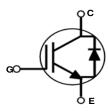
Applications

PDP System

General Description

Using Novel Trench IGBT Technology, Fairchild's new series of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		Ratings	Units
V _{CES}	Collector to Emitter Voltage		330	V
V _{GES}	Gate to Emitter Voltage		± 30	V
I _{Cpulse(1)} *	Pulsed Collector Current @	$T_{\rm C} = 25^{\rm o}{\rm C}$	160	А
$I_{C \text{ pulse(2)}^{\star}}$	Pulsed Collector Current @	T _C = 25°C	220	А
P _D	Maximum Power Dissipation @	$T_{\rm C} = 25^{\rm o}{\rm C}$	149	W
	Maximum Power Dissipation @	$T_{\rm C} = 100^{\rm o}{\rm C}$	60	W
V _{RRM}	Peak Repetitive Reverse Voltage of Diode		330	V
I _{F(AV)}	Average Rectified Forward Current of diode @ $T_C = 100^{\circ}C$		10	А
I _{FSM}	Non-repetitive Peak Surge Current of diode 60Hz Single Half-Sine wave		100	A
T _J , T _{stg}	Operating Junction Temperature and Storage Temperrature		-55 to +150	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction to Case		0.84	°C/W
$R_{\theta JC}(Diode)$	Thermal Resistance, Junction to Case		1.16	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient		40	°C/W

Notes:

1: Repetitive test , Pulse width=100usec , Duty=0.1 2: Half Sine Wave, D< 0.01, pluse width < 5usec *I_C_pulse limited by max Tj

August 2011

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Device N	larking	Device	Package	Packaging Type	Qtv pe	er Tube		x Qty [.] Box
FGA70N33BTD FGA70N33BTDTU		TO-3P)ea			
TGATON	00010		10-51	Tube		Jea		
Electric	al Chai	racteristics of the	IGBT T _C = 2	5°C unless otherwise noted	1	1		T
Symbol		Parameter	Test	Conditions	Min.	Тур.	Max.	Units
Off Charac	teristics							
BV _{CES}	Collector	to Emitter Breakdown Voltag	e V _{GE} = 0V, I _C	₂ = 250μA	330			V
ΔB _{VCES} / ΔT _J	Temperat Voltage	ure Coefficient of Breakdow		$V_{GE} = 0V, I_{C} = 250 \mu A$		0.3		V/ºC
I _{CES}	Collector	Cut-Off Current	V _{CE} = V _{CES}	, V _{GE} = 0V			250	μA
I _{GES}	G-E Leak	age Current	$V_{GE} = V_{GES}$, V _{CE} = 0V			±400	nA
On Charac	toriction							•
V _{GE(th)}		shold Voltage	I _C = 250μA, V _{CE} = V _{GE}		2.3	3.3	4.3	V
			-	$I_{\rm C} = 20$ A, $V_{\rm GE} = 15$ V		1.1		V
	Callester	Collector to Emitter Saturation Voltage		I _C = 40A, V _{GE} = 15V,		1.4		V
	Collector			I _C = 70A, V _{GE} = 15V, T _C = 25°C		1.7		V
			I _C = 70A, V _{GE} = 15V, T _C = 125°C		1.8		v	
Dynamic C	haracteris	tics			1			
C _{ies}	Input Cap					1380		pF
C _{oes}		apacitance	$V_{CE} = 30V, V_{GE} = 0V,$ f = 1MHz			140		pF
C _{res}	Reverse ⁻	Transfer Capacitance				60		pF
Switching	Characteri	istics			1			1
t _{d(on)}	Turn-On I	Delay Time				13		ns
t _r	Rise Time)	$V_{CC} = 200V, I_{C} = 20A, R_{G} = 5\Omega, V_{GE} = 15V, Resistive Load, T_{C} = 25^{\circ}C$			26		ns
t _{d(off)}	Turn-Off I	Delay Time				46		ns
t _f	Fall Time					198		ns
t _{d(on)}	Turn-On I	Delay Time	$V_{CC} = 200V, I_C = 20A,$ $R_G = 5\Omega, V_{GE} = 15V,$ Resistive Load, $T_C = 125^{\circ}C$			13		ns
t _r	Rise Time)				28		ns
t _{d(off)}	Turn-Off I	Delay Time				48		ns
t _f	Fall Time					268		ns
Qg	Total Gate	e Charge				49		nC
Q _{ge}	Gate to E	mitter Charge	$V_{CE} = 200V_{CE}$, I _C = 20A,		6.8		nC
Q _{gc}	Gate to C	ollector Charge	––––– V _{GE} = 15V			17.5	-	nC

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Symbol	Parameter	Test Conditions		Min.	Тур.	Max	Units
V _{FM} Diode Forward Voltage	Diode Forward Voltage	I _F = 10A	T _C = 25°C		1.1	1.5	V
	biodo i olivara toliago		T _C = 125°C		0.95		
t _{rr} Diode Reverse Recovery T	Diode Reverse Recovery Time	I _F =10A, dl/dt = 200A/μs	$T_{C} = 25^{\circ}C$		23		ns
			T _C = 125°C		36		
I _{rr}	Diode Peak Reverse Recovery Current		$T_{\rm C} = 25^{\rm o}{\rm C}$		2.8		А
.11			T _C = 125°C		5.1		
Q _{rr} I	Diode Reverse Recovery Charge		$T_{\rm C} = 25^{\rm o}{\rm C}$		32		nC
			T _C = 125°C		91		1

Typical Performance Characteristics



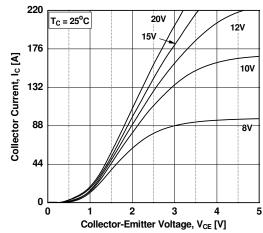


Figure 3. Typical Saturation Voltage Characteristics

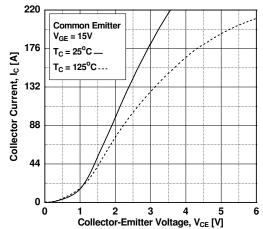


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

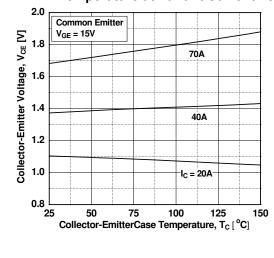


Figure 2. Typical Output Characteristics

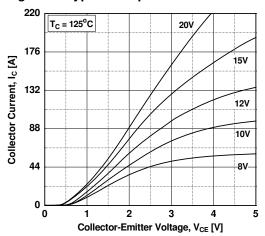
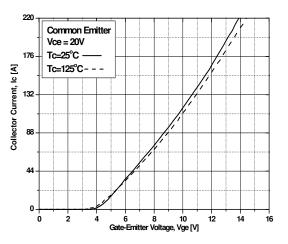
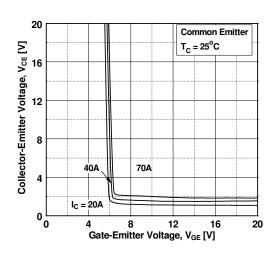


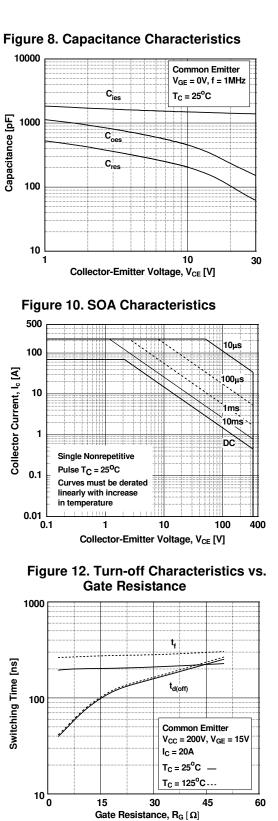
Figure 4. Transfer Characteristics



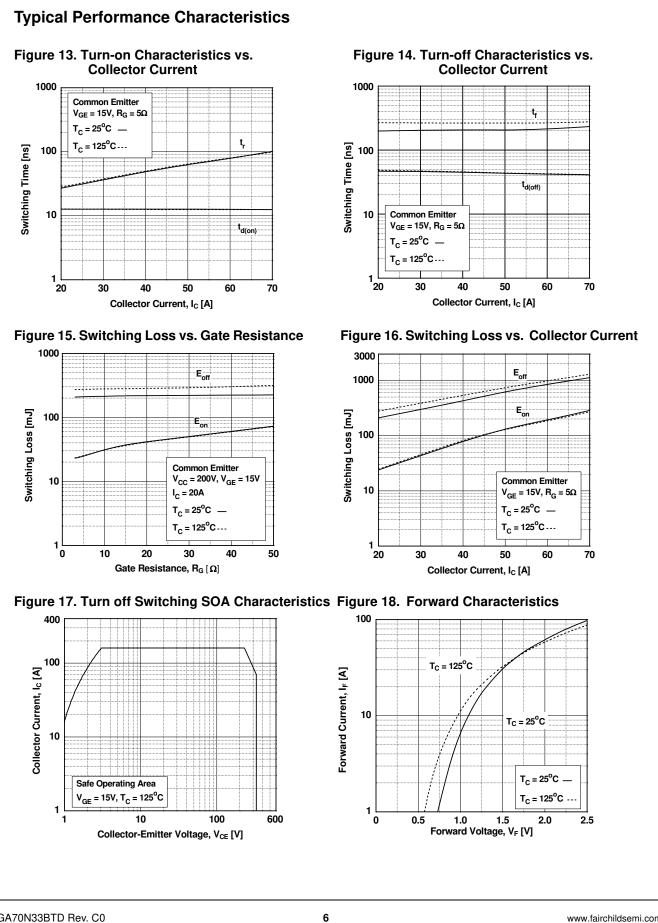




Typical Performance Characteristics Figure 7. Saturation Voltage vs. V_{GE} 10000 20 Common Emitter T_C = 125°C Capacitance [pF] 1000 100 40A 70A I_C = 20A 0 10 0 4 8 12 16 20 Gate-Emitter Voltage, V_{GE} [V] Figure 9. Gate charge Characteristics 15 500 Common Emitter T_C = 25^oC 100 Gate-Emitter Voltage, V_{GE} [V] 6 6 7 $V_{CC} = 100V$ Collector Current, I_c [A] 10 200V 1 0.1 0 10 20 30 40 50 60 0 Gate Charge, Qg [nC] Figure 11. Turn-on Characteristics vs. **Gate Resistance** 200 1000 100 t, Switching Time [ns] Switching Time [ns] 100 10 Common Emitter V_{CC} = 200V, V_{GE} = 15V I_C = 20A $T_{C} = 25^{\circ}C$ — T_C = 125°C 1 30 0 15 45 60 Gate Resistance, $R_G [\Omega]$



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Typical Performance Characteristics

Figure 19. Reverse Recovery Current

Figure 20. Stored Charge

200A/µs

20

Forward Current, IF [A]

di/dt = 100A/µs

30

40

60

45

30

15

0 5

10

Stored Recovery Charge, Qrr [nC]

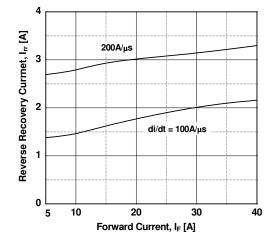
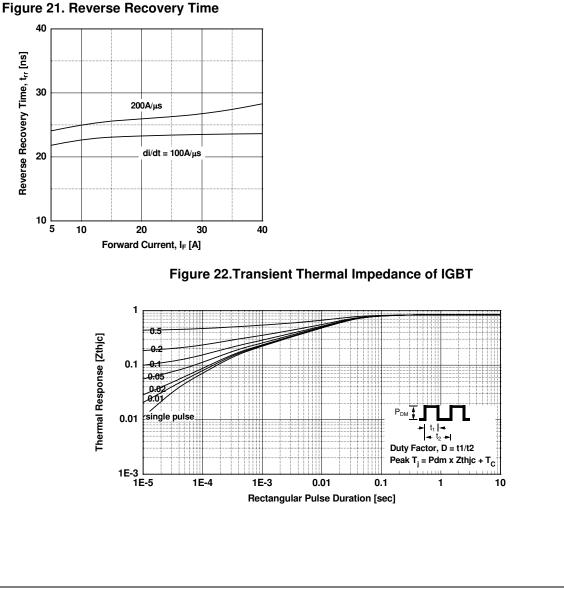
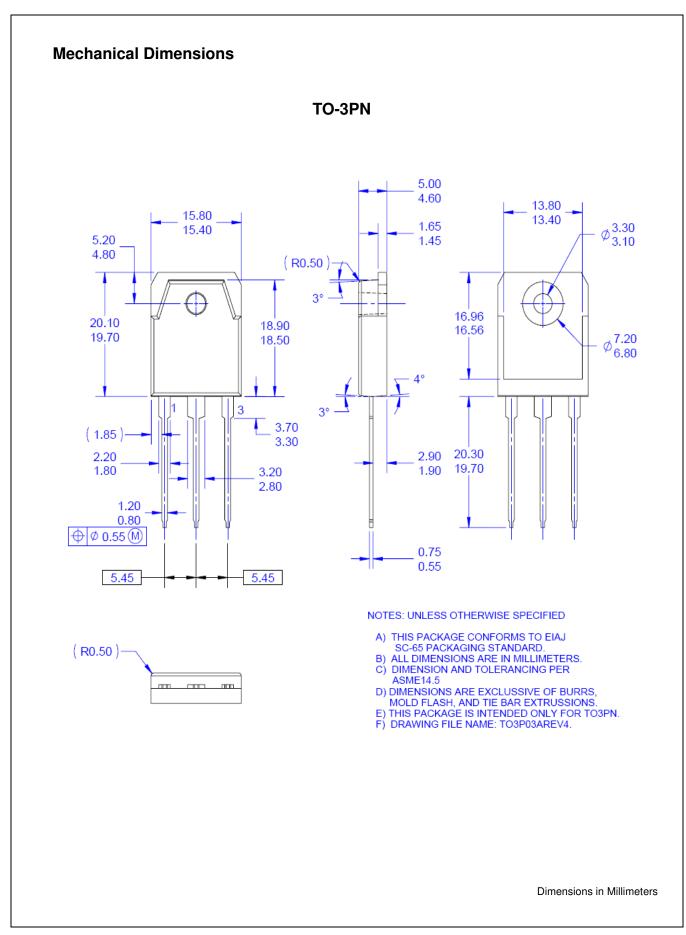


Figure 21. Reverse Recovery Time



FGA70N33BTD Rev. C0





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